

**Themacs**  
Ingénierie

# EM-4 Emissometer

To measure the emissivity  
of **any type of surface**



**For infrared radiation energy flux measurements, it is essential to know the emissivity value**

Emissivity is a parameter that influences the thermal radiation of a surface. This parameter can undergo multiple variations due to the environment. It is therefore necessary to have a device capable of making measurements in situ.

## We tailor EM4 to your needs

Measurement of total emissivity by reflectometric method. The modulated flux method is independent of the temperature of the sample. A sample can be measured outdoors regardless of its temperature. Patented device (FR1251476)

**The emissometer allows these users to :**

- Measuring** total directional emissivity
- Calculate** the total hemispheric emissivity
- Evaluate** the specular or scattering character of the surface

**The device can measure high and low emissivity.**

As an option, emissivity can be measured in specific bands (e.g. 8-12 $\mu$ m).

**Supplied with power supply,  
4 reference surfaces and carrying case**



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